

Whisker-Inpenetrable Metal Cap Process for Electronic Assemblies

Bob Landman, Gordon Davy, Dennis Fritz
LDF Coatings, LLC

Copyright 2010 LDF Coatings, LLC All Rights Reserved



Abstract

There are many negatives due to the Pb-free RoHS legislation. There are, still today, no good options available to high-rel OEMs for what are now Pb-free COTS components and assemblies. Component-by-component “mitigation” of tin whisker growth risk is very labor-intensive and, at best, it worked only when the majority of components were not Pb-free.

The *ideal universal process* should be much less expensive and should be applicable to an entire assembly, not just “mitigating” the risk of whisker growth but *preventing* whiskers from growing, with a *permanently impenetrable coating*.

A process is described that deposits a nickel (or other whisker-impenetrable metal) cap *selectively* over all Pb-free tin and high-tin alloys, but will not deposit nickel on any insulating surfaces (component bodies, solder mask, etc..) of an assembly.

What Is The Problem?

- Pb-free tin on electronic assemblies can grow whiskers that can cause circuit failure.
- Because high-reliability assemblies have long design life, whisker problem is of particular concern to designers.
- Regulations and economics have resulted in many otherwise desirable COTS electronic components *and assemblies* being available *only* with
 - Pb-free tin as the termination finish OR
 - Pb-free SAC solder balls under BGAs
- High-rel customers lack clout – don't buy enough.
 - Often impractical to procure desired SnPb termination finish or BGA balls.

What is the Solution?

A paradigm shift is needed

Is mitigation prevention ?

- Component-by-Component mitigation is unreliable and difficult to manage
- LDF Coatings solution protects the entire assembly at once

Tin Whisker Mitigation

- COTS Components
 - 85% have a tin termination finish.
 - If OEM uses SnPb solder, whisker risk is primarily for unsoldered termination areas
- COTS Assemblies
 - BOM cannot be “scrubbed,” hence *no* mitigation.
 - If “dual-use,” has Pb-free (high-Sn) solder.
- “Mitigate” means “reduce” not “prevent.”
- If prevention is possible, why **mitigate?**

Mitigating Whisker Risk Component-By-Component

If Pb-free Sn is not allowed

OEMS must use:

- No COTS assemblies
- Expert “scrubbing” of OEM-BOM to catch non-conforming components
- 100% receiving inspection to confirm that components match spec

Mitigating Whisker Risk Component-By-Component

Pb-free components must be subjected to a process that modifies termination finish to include Pb.

- Chip components: AEM process
 - Single source
 - High setup costs
 - Logistics and delays
- Larger components: solder dipping
 - High setup costs
 - Many components can probably withstand manual dipping
 - Risk of undetected damage from heat or handling
 - Logistics and delays

Mitigating Whisker Risk Component-By-Component

If contract allows Sn, OEM must do *more*:

- Have experts “scrub” the OEM-BOM looking for “high-risk” components.
- Pinsky model identifies numerous risk areas
 - Examples: Ni underlayer, reflow, spacing
- Verify that received components match product descriptions.
- Cannot mitigate risk for COTS assemblies.

All agree that risk with Pb-free Sn on component terminations can at best only be mitigated.

Mitigating Whisker Risk Component-By-Component

Kim et al, recommend electroplating instead of solder dip.

- Where Pb-free cap layer over Sn termination finish must:
 1. Remain **solderable** during storage
 2. Remain **impenetrable**, even as IMC grows
- Investigated Ni, Au, Pd over 6 μm (240 $\mu\text{in.}$) Sn

1. Solderability During soldering, will thicker Sn under-layer (which expands as it melts), break the cap?

Example: Oxide on Sn not attacked by Type R flux, but does break up.
Ni – **NO** If cap is continuous, but not for islands

2. Impenetrability

Ni, Au, Pd: **YES!**

Pb: **NO** (Li, AEM, anecdote, no photos)

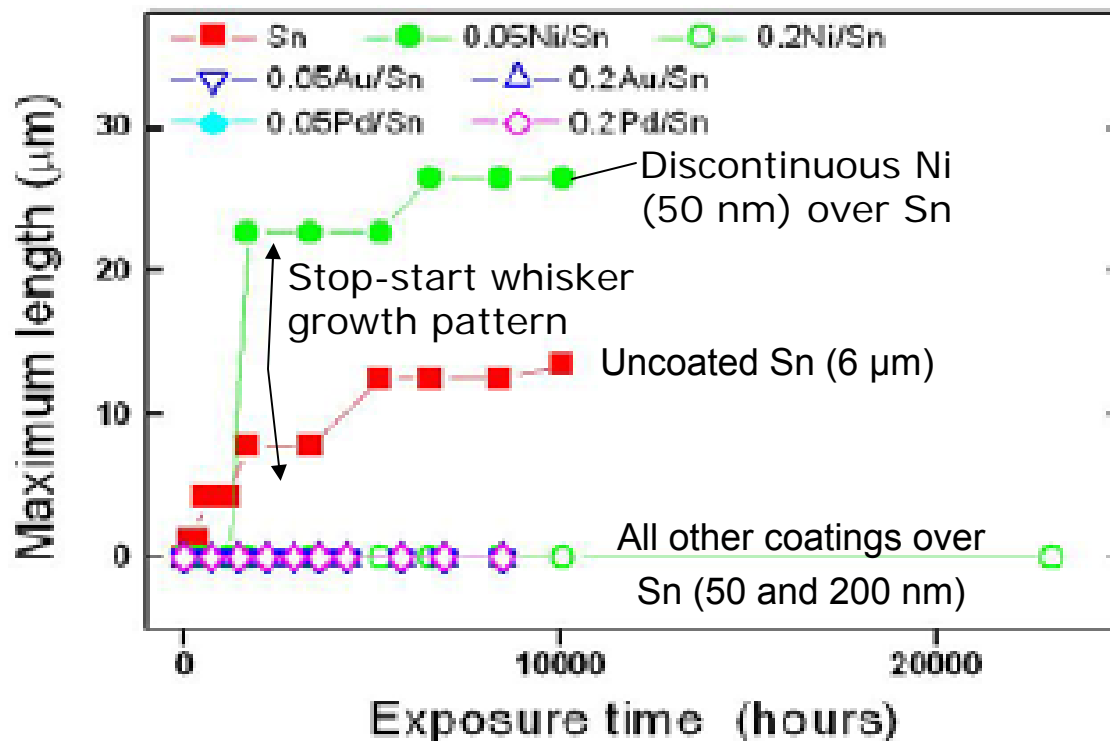
Mitigating Tin Whisker Risk

(Kim, et al)

Cap Type & Attributes	50 nm	200 nm
Ni Electrodeposit continuity? WB solderable (8 hr steam)? Whisker penetration?	No – Islands Significant decrease Promotes whiskers	Yes Unsolderable None in 5 years
Au Electrodeposit continuity? WB solderable (8 hr steam)? Whisker penetration?	<i>Mostly AuSn₂ as deposited (1 day)</i> Yes Yes None in 4 years	<i>Largely AuSn₂ after 2000 hours</i> Yes Yes None in 4 years
PD Electrodeposit continuity? WB solderable (8 hr steam)? Whisker penetration?	Very little PdSn ₄ IMC as deposited Yes Yes None in 4 years	PD reaction rate with Sn < Au > Ni Yes Yes None in 4 years

200 nm Ni Cap Impenetrable For Five Years

Kim, et al



Copyright 2010 LDF Coatings, LLC All Rights Reserved

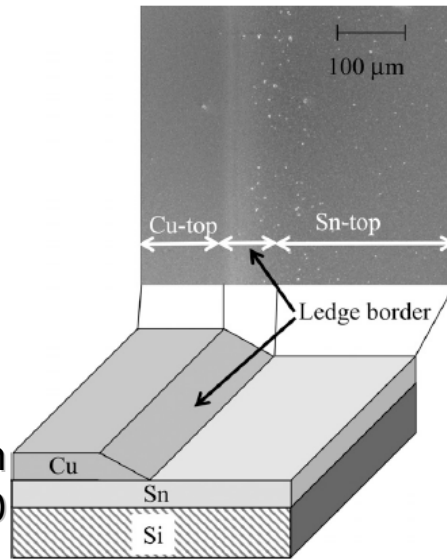
LDF
COATINGS

www.LDFcoatings.com

600 nm Copper Cap Penetrated In 3 Days (Reinbold et al)

White spots are whiskers seen at 49 days; first whisker on Cu-top seen at 3 days

600 nm thick layer of Cu vapor deposited with shadow mask over 1200 nm Sn (w/10 nm Cr adhesion layer)



- ∴ For Ni,
- 1) Sn whisker is not an irresistible force, or
 - 2) IMC precipitation does not deform Sn above critical nucleation value

Virtually no growth of whiskers far from ledge. Cu diffused away from ledge; whiskers were found growing ahead of where Cu could be detected ⇒ **IMC**

precipitation plastically deforms nearby Sn; whisker nucleates when stress exceeds a critical value.

Cu and Ni diffusion rate difference in Sn cannot explain huge whisker penetration difference.

The Prevention Challenge

Develop a practical process that can be applied to an assembly to protect it from whisker-induced shorts.

- Coat all tin with a material that permanently prevents whiskers from penetrating from below.
- Prospects for a non-material added process are gloomy.
- No more mitigation!

The Ideal Prevention Process For Assemblies

- Permanently suppresses whisker growth (with supporting data)
- Eliminates BOM scrubbing
- Eliminates testing for Pb-free Sn at receiving
- Eliminates all mitigation efforts
- Solves whisker problem with COTS assemblies
- Applies to all electronic assemblies
- Covers all tin – no shadowing
- Negligible risk of damage to assembly function, reliability, and legibility
- Negligible fixed and maintenance costs for equipment

Copyright 2010 LDF Coatings, LLC All Rights Reserved



The Ideal Prevention Process For Assemblies

- Small equipment footprint
- Inherently safe – doesn't use exotic chemicals (i.e., not already in use in electronics industry)
- Simple training of work force
- Quick: handling time req't \gt 5 minutes/assembly, so no bottleneck
- Can be performed immediately after cleaning and before conformal coating; no additional cost for masking

What would it be worth per square foot?

Whisker Prevention Coating Processes For Assemblies

(Not Mitigation!)

Three Game Changing Options:

1. “ALD-Cap” conformal ceramic
- Sundew Technologies
2. “Whisker-Tough” conformal polymer
- Smith & Co.
3. Selective metal cap
- LDF Coatings, LLC

Sundew ALD-Cap

- Thin layer (~ 200 nm) of ceramic applied after proper surface prep.
- Takes only minutes to apply
- Batch process
- Coating properties unlikely to change with temp, humidity, or time
- Substitutes for polymer conformal coating
- Rework not a problem
- Process inherently coats under BGAs

Copyright 2010 LDF Coatings, LLC All Rights Reserved



www.LDFcoatings.com

Smith & Company

“Whisker Tough”

- Penetration and adhesion of flexible films was studied *extensively* to determine formulation requirements
 - Unique concept: tent and redirect a whisker’s growth rather than prevent its growth – no penetration.
 - Coating material formulated per findings to give at least 0.1 mil coverage along sharp edges of terminations (thixotropy).
- Replaces conventional conformal coating
 - ∴ marginal costs involve only extra cost of material, if any
- FOD virtually eliminated with specially designed dip tank
 - A reasonable amount of operator training required
 - Pot life \leq 3 hrs (extendable indefinitely by replacing dragout)
 - Overnight bake w/ temperature ramp, incl. 2 hrs at 85°C for full cure
 - Compliance verification
 - Completely transparent
 - Any area of non-coverage findable by non-fluorescence under UV illumination
 - Proper composition and cure easily verified by measuring coating modulus
 - Rework comparable to conventional urethane CC’s

LDF Coatings

Selective Metal Cap

Available whisker-preventing cap processes:

- Ceramic – “ALD-Cap”
 - Polymer – “Whisker-Tough”
 - Metal Apply to a functioning assembly
1. Must apply to surfaces *selectively*:
 - Must coat all exposed tin
 - OK to coat other metals (mask contact areas)
 - Must not coat any insulating surface
 2. Must be proven whisker-impenetrable

Solderability, ductility not requirements!

1. Reduced to practice; patent applied for
2. Whisker penetration data:
 - Kim: No penetration of 200 nm Ni in 5 years
 - Chason: Penetration of 600 nm Cu in 3 days
 - Li: Penetration of Pb

Selective Metal Cap Layer Process For Coating Tin

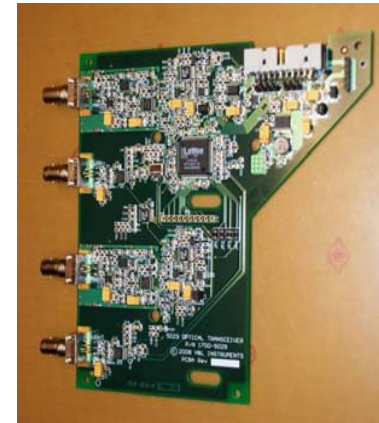
- Must be a chemical process
- Theoretically, three options
 - Electrochemical
 - All tin surfaces must be electrically connected
 - Immersion (replacement)
 - Few candidates; too thin
 - **Electroless (autocatalytic)**
 - Except with special procedures, does not deposit on insulators
 - Numerous metals known to electrolessly deposit on tin
 - Ni and Pd are known to be impenetrable

What metal would *you* try first?

What experiment would *you* try first?

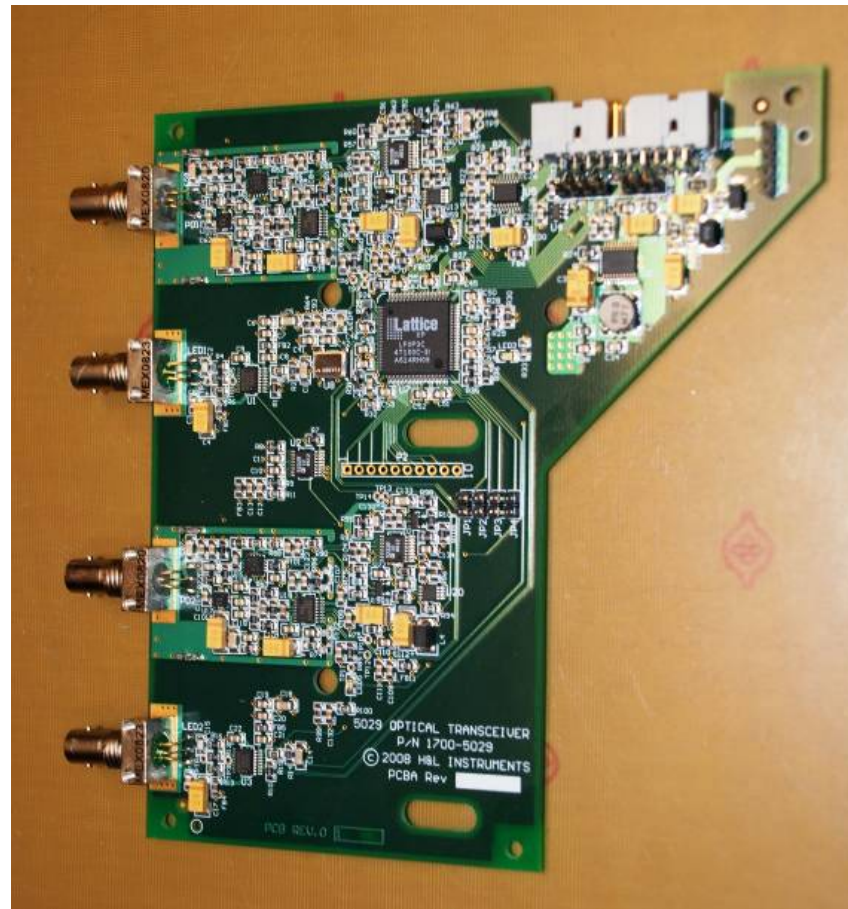
LDF Coatings, LLC is Formed

- Landman, Davy, Fritz
- Provisional patent applied for
 - ↳ June 26, 2010 reduced to practice on an H&L Instruments fiberoptic pcb
 - Masked with tape and removable mask coating
 - Uses conventional cleaning
 - Total immersion 1 hr. \Rightarrow $\sim 25 \mu\text{m}$ (1 mil) Ni deposited
- Actual estimated deposit thickness *needed* $\sim 1\text{-}2 \mu\text{m} < 5 \text{ min.}$
- **Kim et al. found no penetration of 200 nm (0.2 μm) Ni in 5 yrs.**
 - Ni reacts with air to form a protective oxide layer
 - Ni reacts with tin very slowly to form IMC; reaction rate drops as $t^{1/2}$



Plenty of metallic Ni cap layer will remain in 30 years

Process Applied To This Commercial Product

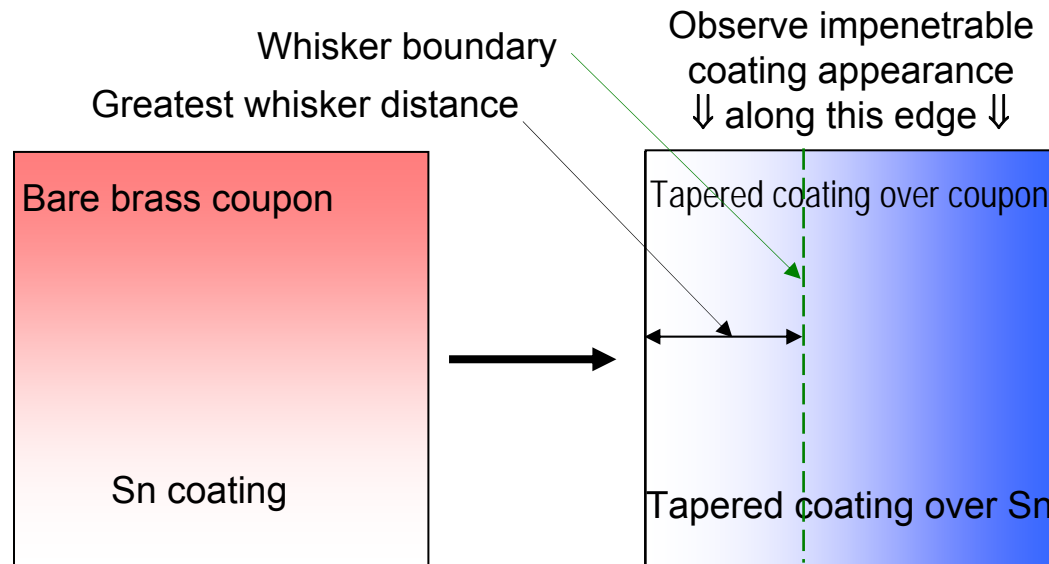


Copyright 2010 LDF Coatings, LLC All Rights Reserved

LDF
COATINGS

www.LDFcoatings.com

Concept: Testing For Permanent Impenetrability



L – Coupon with coating of tapered thickness of Sn

R – Coupon with coatings of perpendicular tapered thicknesses of Sn and impenetrable coating.

Greatest whisker distance is distance from edge to farthest whisker in a single observation.

Whisker boundary is greatest whisker distance remaining unchanged for three successive monthly observations.

Copyright 2010 LDF Coatings, LLC All Rights Reserved



www.LDFcoatings.com

How LDF Coatings Process Compares to Ideal

- Eliminates BOM scrubbing and testing components for Pb-free Sn at receiving
- Solves termination finish whisker problem with COTS assemblies
- *Permanently* suppresses whisker growth (Kim *et al.* > 5 yrs for 200 nm Ni)
- Applicable to all electronic assemblies (mask, and add components later if necessary)
- All tin is covered – no shadowing – hot aqueous immersion
- Risk of damage to assembly function, reliability, and legibility is negligible
- Fixed and maintenance costs negligible
- Small equipment footprint
- Process is inherently safe – does not use exotic chemicals (i.e., not already in use in electronics industry)
 - Long history, wide use of electroless Ni

Copyright 2010 LDF Coatings, LLC All Rights Reserved



How LDF Coatings Process Compares to Ideal

- Training of work force is simple – **expect a broad process window**
- Quick, so no bottlenecks: time requirement > 5 minutes per assembly
- Process can be performed immediately after cleaning and before conf. coating;
no additional cost for masking
- Easy cleanup of assembly for next process step – **water and steam then dry**
- Built-in practical compliance verification – **bubbles, coated Cu looks different (+XRF)**
- No interference w/ rework - **masking allows components to be added later**

LDF Coatings Next Steps

- Provisional patent applied for
- Continue research and publish, while seeking select companies for participation in trials
- Seek a corporate licensing partner
 - For more R&D and to commercialize
 - Verify min. thickness for permanent suppression
 - Does IMC prevent penetration?
 - Explore process window for robustness
 - Effects of porosity, P content, etc.
 - Pd over Ni, Ni-Pd alloy for extra corrosion resistance?
 - To assume marketing, production, installation, distribution, customer service (including recycling)

Problem and Solution Review

- High-rel assemblies risk tin whiskers from COTS components and sub-assemblies.
- Preventing whisker risk with an ideal process on an assembly beats “mitigating” risk component-by-component.
- Prepared and presented requirements list for an ideal process for assemblies.
- Analyzed three processes for assemblies: ceramic, polymer, and selective metal coating.

Problem and Solution Review

- Process for selective deposition of a thin cap layer of whisker-impenetrable metal, coating all tin but not insulating surfaces
 - Process described
 - Reduced to practice
 - Compares favorably to the ideal
 - Assemblies are likely to remain permanently impenetrable
- LDF Coatings, LLC was formed to
 - Publicize the process
 - Seek assemblies from OEMs for further testing and to ensure that the process does not impair function
 - Seek a corporate licensing partner
 - Promote the implementation.

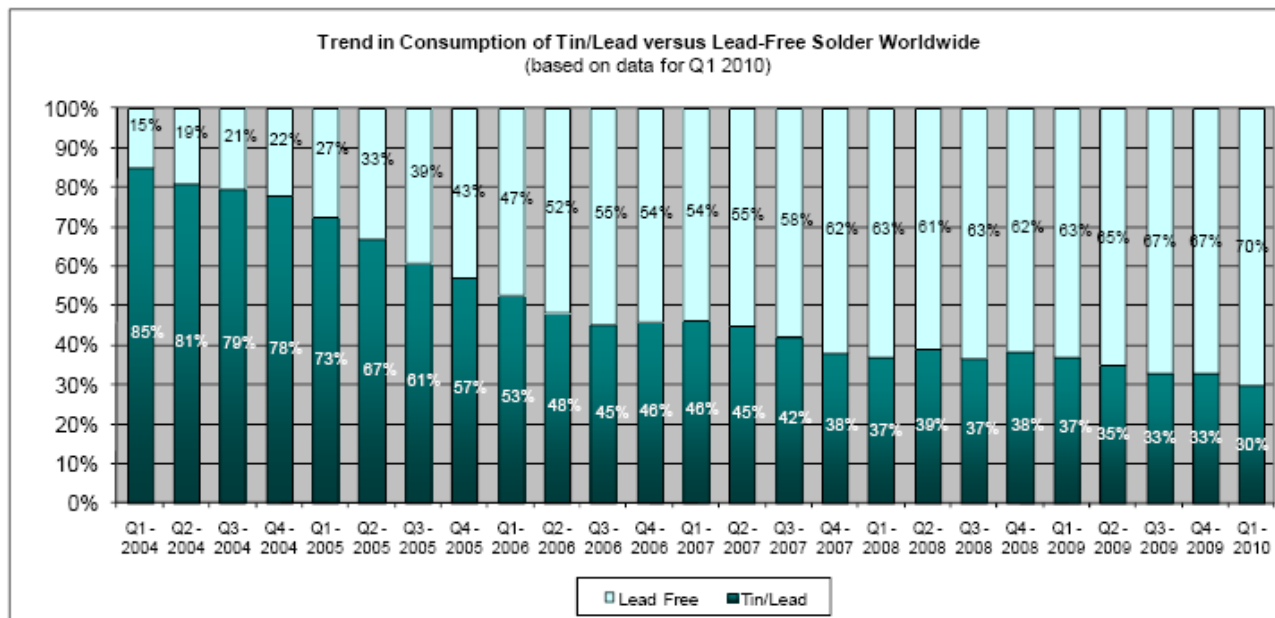


Footnote

Who says we won't be able to buy SnPb solder?

Lead-Free Solder Market has Stabilized

The growing proportion of lead-free solder in the marketplace has slowed and now stands at around 70 percent of worldwide solder consumption in Q1 2010.



Source: IPC Global Quarterly Solder Statistical Program, *Electronics Industries Market Data Update*, Spring 2010. Free to members at <http://www.ipc.org/Update>.

Copyright 2010 LDF Coatings, LLC All Rights Reserved



Copyright 2010 LDF Coatings, LLC All Rights Reserved

